Docket No.: 57454-947

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Koichiro NARIMATSU

Serial No.: Divisional of

Appln. Serial No. 09/570,463

Group Art Unit: Not yet assigned

Filed: June 26, 2003

Examiner: Not yet assigned

For:

SEMICONDUCTOR DEVICE AND MANUFACTURING METHOD THEREOF, AND

REGISTRATION ACCURACY MEASUREMENT ENHANCEMENT METHOD

INFORMATION DISCLOSURE STATEMENT

Mail Stop Patent Application Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached form PTO-1449. It is respectfully requested that the references be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

The references were cited by or submitted to the U.S. Patent and Trademark Office in parent application Serial No. 09/570,463, filed May 12, 2000, which is relied upon for an earlier filing date under 35 USC 120. Thus, copies of these references are not attached. 37 CFR 1.98(d).

Respectfully submitted,

MCDERMOTT, WILL & EMERY

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Date: June 26, 2003

INFORMATION DISCLOSURE CITATION IN AN APPLICATION					ATTY. DOCKET NO. 57454-947	D	SERIAL NO. Divisional of Appln. Serial No. 09/570,463			
					APPLICANT Koichiro NARIMATSU					
(PTO-1449)					FILING DATE June 26, 2003	June 26, 2003 Not yet as			signed	
			Old Operation and the Control of the	U.S. PATEN	T DOCUMENTS					
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code2 (# known)		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document			Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
		US	5,892,291	4/1999	Narimatsu et al	Narimatsu et al.		_		
		US	5,952,134A	9/1999	Hwang					
		US	6,083,807A	7/2000	Hsu	Hsu				
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FOREIGN PATENT DOCUMENTS										
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes -Number 4 -Kind Codes (if known)		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear		Translation		
		1	JP 9-74063	3/1997				Yes	No	
			JP 6-176996	6/1994						
			JP 02000010254A	1/00	Takahata et al.					
		<u> </u>	JP 11-28869	10/99						
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	<u> </u>	<u> </u>	OTHER A	RT (Including Autho	r Title Date Pertinent Pages F	tc.)		<u> </u>		
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.) EXAMINER'S Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine,										
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EXAMINER					DATE CONSIDERED					

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.